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## TRANSMITTAL FORM

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Total Number of Pages in This Submission

Application Number

10/609,311

Filing Date

June 26, 2003

First Named Inventor

Donald L. Yates

Art Unit

2811

Examiner Name

Unknown

Attorney Docket Number

MI22-2236

### ENCLOSURES

(Check all that apply)

☐

Fee Transmittal Form

☐

Fee Attached

☐

Amendment/Reply

☐

After Final

☐

Affidavits/declaration(s)

☐

Extension of Time Request

☐

Express Abandonment Request

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Supplemental  
Information Disclosure Statement

☐

Certified Copy of Priority  
Document(s)

☐

Reply to Missing Parts/  
Incomplete Application

☐

Reply to Missing Parts  
under 37 CFR 1.52 or 1.53

☐

Drawing(s)

☐

Licensing-related Papers

☐

Petition

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Petition to Convert to a  
Provisional Application

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Power of Attorney, Revocation

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Change of Correspondence Address

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Terminal Disclaimer

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Request for Refund

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Landscape Table on CD

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After Allowance Communication to TC

☐

Appeal Communication to Board  
of Appeals and Interferences

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Appeal Communication to TC  
(Appeal Notice, Brief, Reply Brief)

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Proprietary Information

☐

Status Letter

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Other Enclosure(s) (please identify  
below):

PTO Return Receipt Postcard  
Form PTO-1449 w/copies of  
cited references

Remarks

Customer No. 021567

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### SIGNATURE OF APPLICANT, ATTORNEY, OR AGENT

Firm Name

Wells St. John P.S.

Signature

Printed name

Robert C. Hyta

Date

10/25/04

Reg. No.

46,791

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This collection of information is required by 37 CFR 1.5. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.11 and 1.14. This collection is estimated to 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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EV372470038



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent Application Serial No. .... 10/609,311  
Filing Date ..... June 26, 2003  
Inventor ..... Donald L. Yates  
Assignee ..... Micron Technology, Inc.  
Group Art Unit ..... 2811  
Examiner ..... Unknown  
Attorney Docket No. .... MI22-2236  
Customer No. .... 021567  
Title: Semiconductor Processing Patterning Methods and Constructions

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

References -- See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR §1.56. Copies of all references are attached. No admission is made regarding whether all the listed references are prior art.


Citation of the referenced art is respectfully requested.

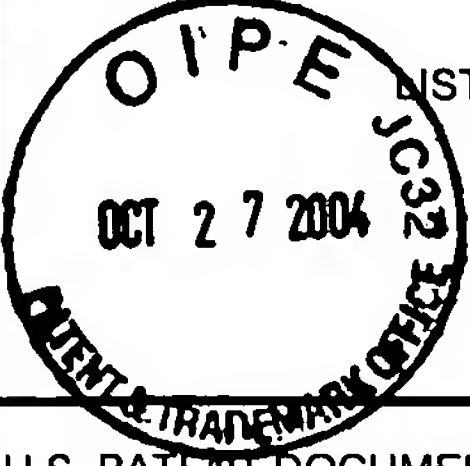
This Supplemental Information Disclosure Statement is being filed before the mailing date of a first Office Action. There, no fee is believed to be required.

However, in the event that a fee is required for filing this Information Disclosure Statement, please charge the fee specified under 37 C.F.R. § 1.17(p) to Deposit Account No. 23-0925.

Respectfully submitted,

Dated: 10/25/04

By:   
Robert C. Hyta  
Reg. No. 46,791

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2236	SERIAL NO. 10/609,311		
 <p style="margin-top: 10px;">LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)</p>				APPLICANT: Donald L. Yates			
				FILING DATE June 26, 2003	GROUP 2811		
<b>U.S. PATENT DOCUMENTS</b>							
*Examiner's Initials	AA	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	3,349,474	12/1963	D. H. Rauscher			
	AB	5,904,517	05/1999	Gardner et al.	438	197	
	AC	5,998,264	12/1999	Wu	438	260	
	AD	6,180,465 B1	01/2001	Gardner et al.	438	291	
	AE	6,207,485 B1	03/2001	Gardner et al.	438	216	
	AF	6,548,854 B1	04/2003	Kizilyalli et al.	257	310	
	AG						
	AH	2003/0045060 A1	03/2003	Ahn et al.	438	287	
	AI	2003/0045078 A1	03/2003	Ahn et al.	438	585	
<b>FOREIGN PATENT DOCUMENTS</b>							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes      No
	AJ	EP 0 851 473 A2	01/1998	EPO			X
	AK						
	AL						
<b>OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)</b>							
	AM		Chang et al., Silicon surface treatments in advanced MOS gate processing, Microelectronic Engineering, (2004), pages 130-135				
	AN		Lemberger et al., Electrical characterization and reliability aspects of zirconium silicate films obtained from novel MOCVD precursors, Microelectronic Engineering (2004), pages 315-320				
	AO		Lu et al., Effects of the TaN <sub>x</sub> interface layer on doped tantalum oxide high-k films, VACUUM (2004), pages 1-9				
EXAMINER		DATE CONSIDERED					
<p><small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small></p>							

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	AA						
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	AG						
	AH						
	AI						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation Yes      No
	AJ						
	AK						
	AL						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AM		Robertson et al., Atomic structure, band offsets, growth and defects at high-K oxide:Si interfaces, Microelectronic Engineering (2004) pages 112-120				
	AN		Singh et al., High and Low Dielectric Constant Materials, The Electrochemical Society <i>Interface</i> , Summer 1999, pages 26-30				
	AO						
EXAMINER		DATE CONSIDERED					
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							